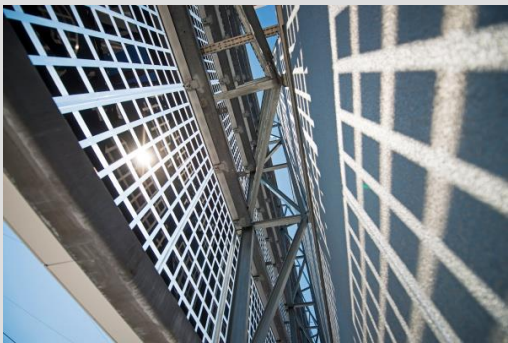
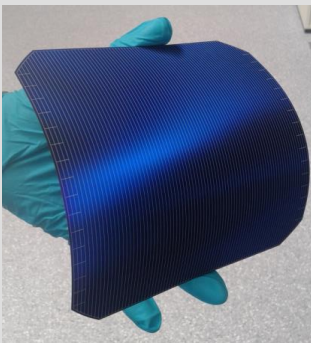
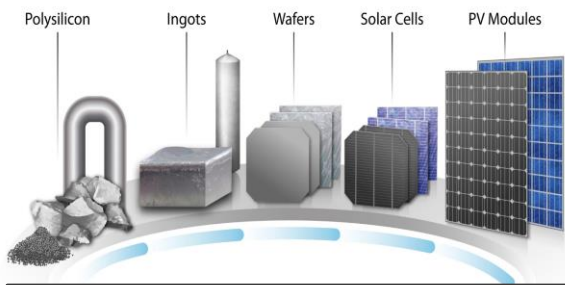


# Technologie Evolutives et Disruptives pour les prochaines g n rations de cellules solaires Silicium

M. Despeisse, on behalf of CSEM and EPFL/pvlab research teams



## HIGH PERFORMANCE LOW COST

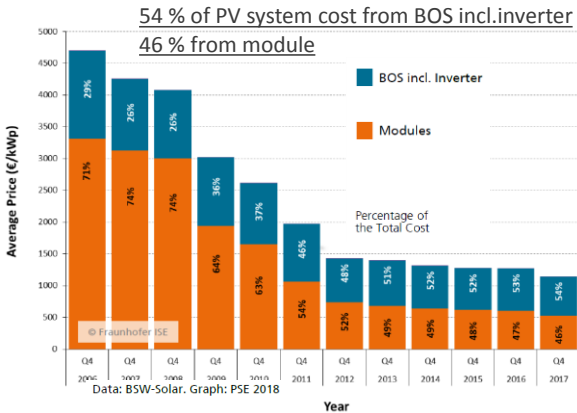


**MATERIALS, PROCESSES and TECHNOLOGIES**  
For COST-COMPETITIVE MANUFACTURING

Low \$/Wp

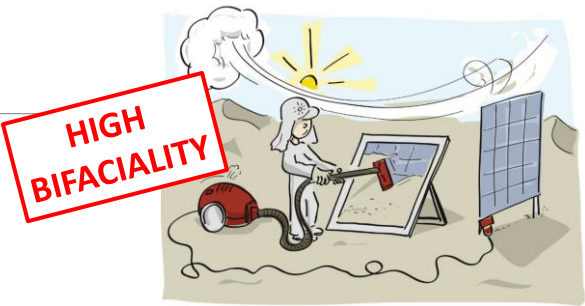
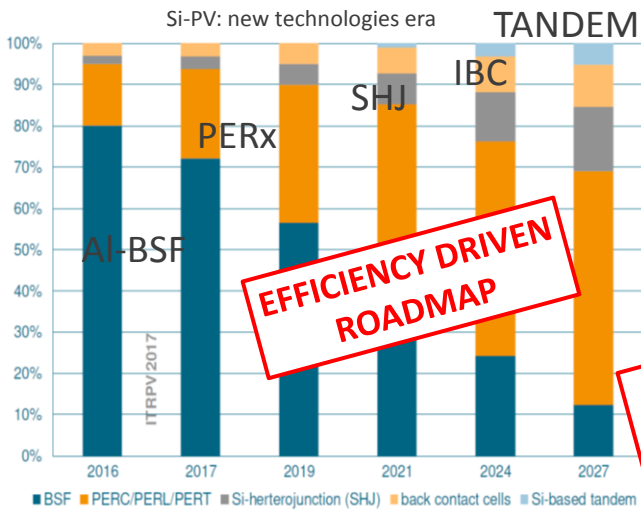
HIGH EFFICIENCY

Low \$/kWh



**HIGH FIELD PERFORMANCE**

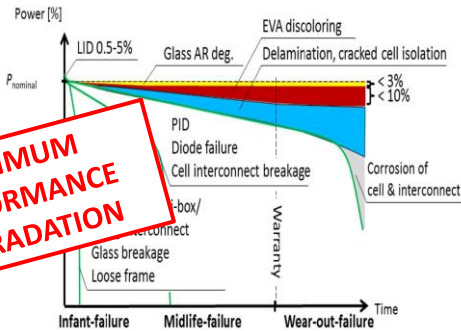
HIGH PERFORMANCE LOW COST



HIGH BIFACIALITY

EFFICIENCY DRIVEN ROADMAP

MINIMUM PERFORMANCE DEGRADATION



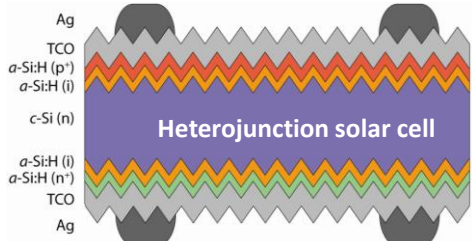
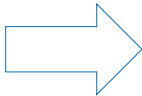
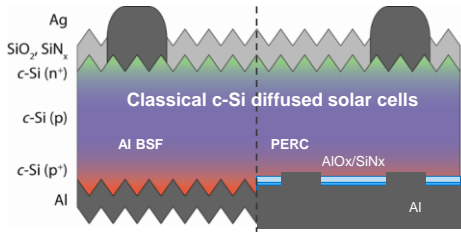
csem

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STEP 1: IMPLEMENTING PASSIVATING CONTACTS & GOING BIFACIAL

Direct contact between c-Si and metal  
**Recombinative contact**  
→ Lower operating voltage &  $V_{oc}$

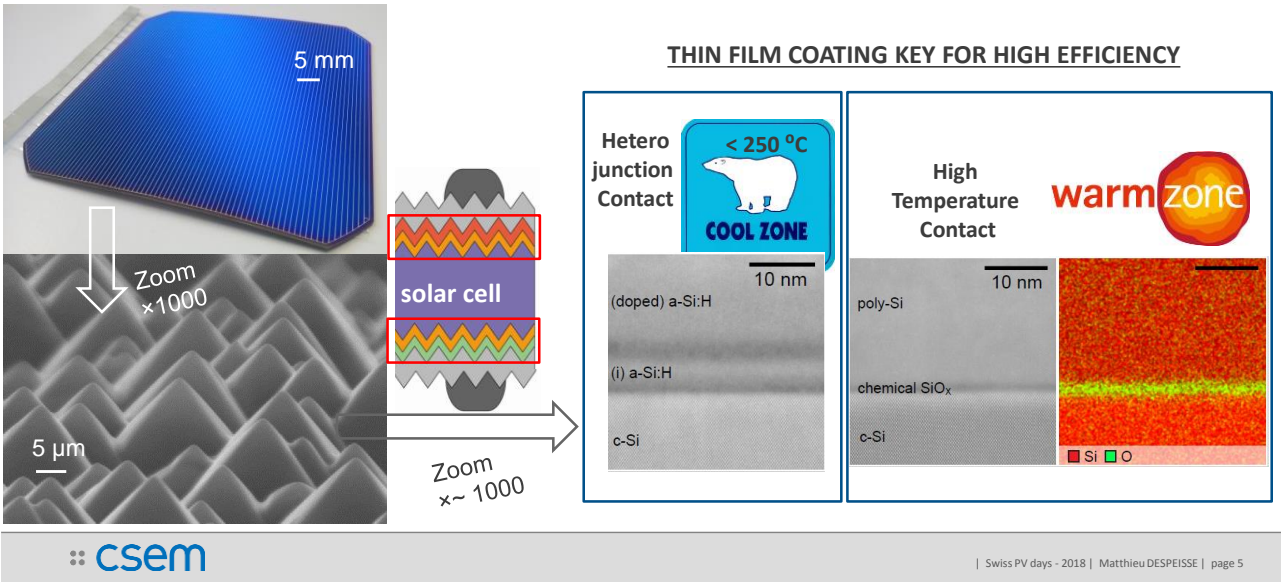
Heterocontact between c-Si and metal  
**Passivating contacts**  
→ Higher operating voltage &  $V_{oc}$   
**Bifacial structure**



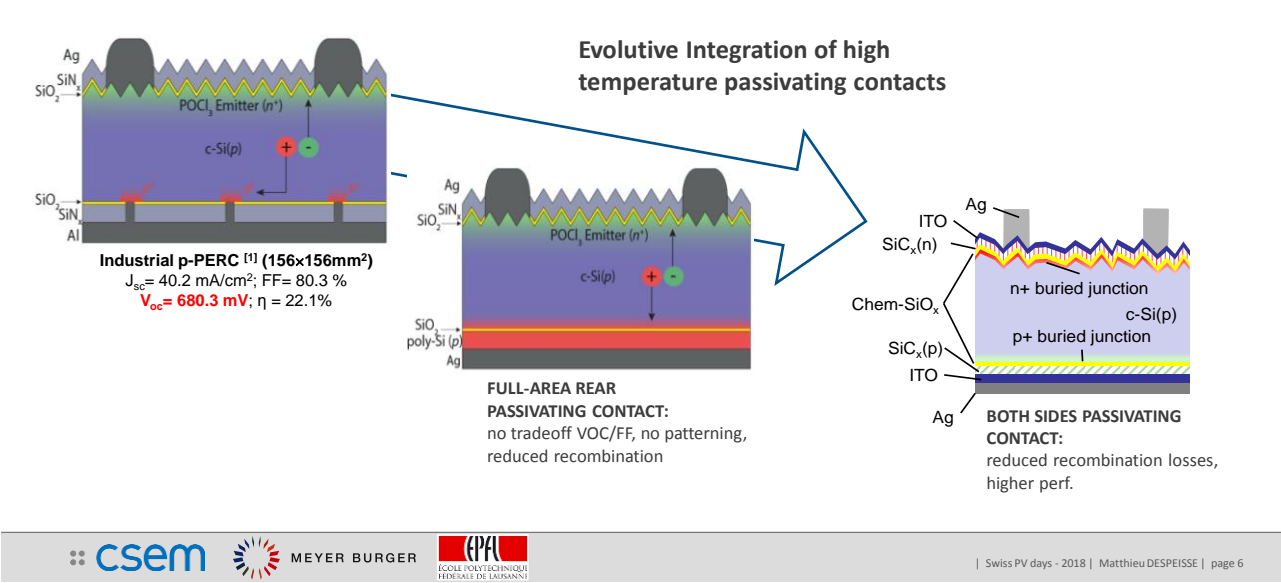
csem

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STEP 1: IMPLEMENTING PASSIVATING CONTACTS & GOING BIFACIAL



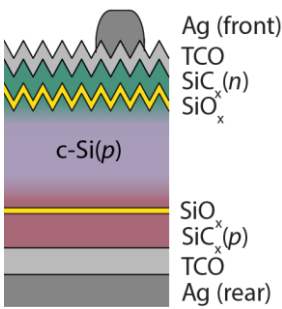
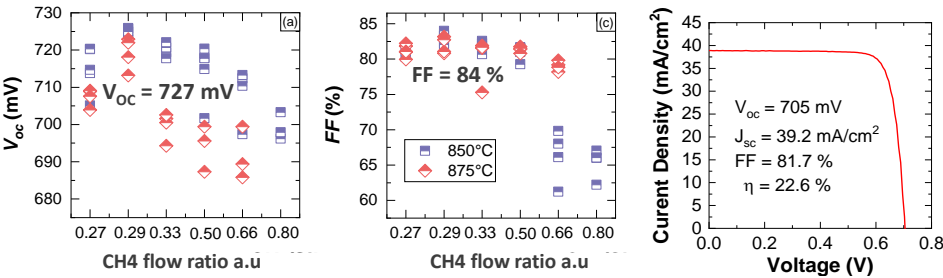
STEP 1: IMPLEMENTING PASSIVATING CONTACTS & GOING BIFACIAL



STEP 1: IMPLEMENTING PASSIVATING CONTACTS & GOING BIFACIAL

SiOx/SiCx high temperature passivating contacts developed in EPFL/CSEM:  
high operating voltages FF up to 84 %,  $V_{oc}$  of 727 mV on flat wafers :  
high passivation, low transport losses achieved.

Target: achieve similar properties on textured surfaces + limit front-side parasitic absorption.

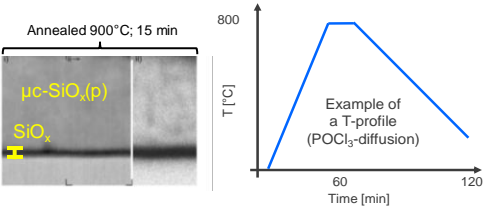


➡ See poster of Josua Stuckelberger - EPFL

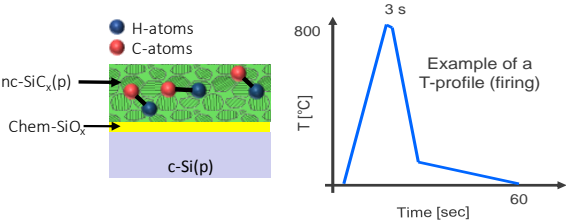
STEP 1: IMPLEMENTING PASSIVATING CONTACTS & GOING BIFACIAL

TOWARDS LEAN PROCESS FLOW INTEGRATION of  
HIGH TEMPERATURE PASSIVATING CONTACTS

Approach 1:  
Co-annealing with  $POCl_3$  process for  
emitter formation



Approach 2:  
Co-firing with front side Ag-paste



➡ See poster of Josua Stuckelberger - EPFL

1 : PASSIVATING CONTACTS & BIFACIAL

> 24 % R&D level

CAPEX reduction

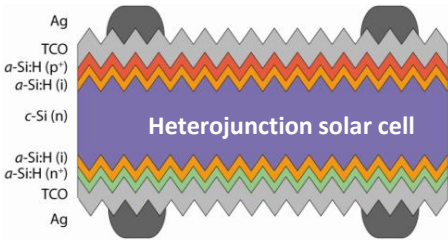
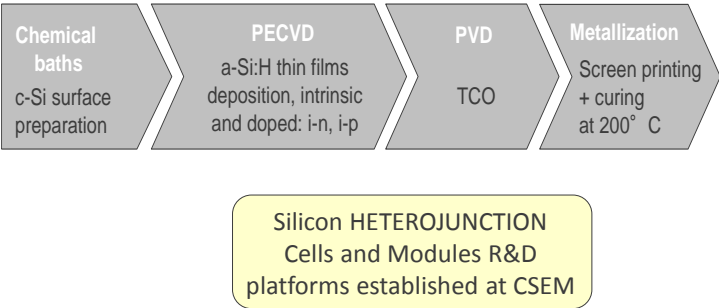
Metallization/ Interco costs

Mass prod. demo

Upgrade roadmap

Capitalize on Tcoeff, bifacial, thin wafer

DISRUPTIVE APPROACH : SILICON HETEROJUNCTION  
LEAN PROCESS FLOW, HIGH PASSIVATION



1 : PASSIVATING CONTACTS & BIFACIAL

> 24 % R&D level

CAPEX reduction

Metallization/ Interco costs

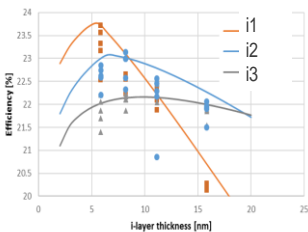
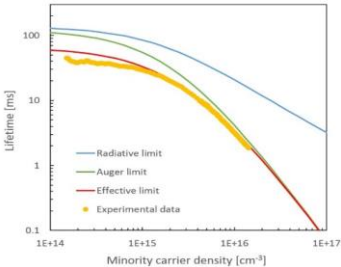
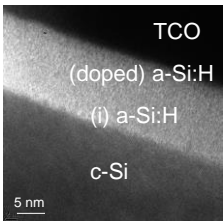
Mass prod. demo

Upgrade roadmap

Capitalize on Tcoeff, bifacial, thin wafer

Best cell produced so far in CSEM:  
**24.1 %**  
 $V_{oc} = 727\text{ mV}$ ,  
 $J_{sc} = 40.8\text{ mA/cm}^2$ ,  
 $FF = 81.1\%$

Processes for a-Si:H deposition key to achieve required opto-electronic properties.



1 : PASSIVATING CONTACTS & BIFACIAL

> 24 % R&D level

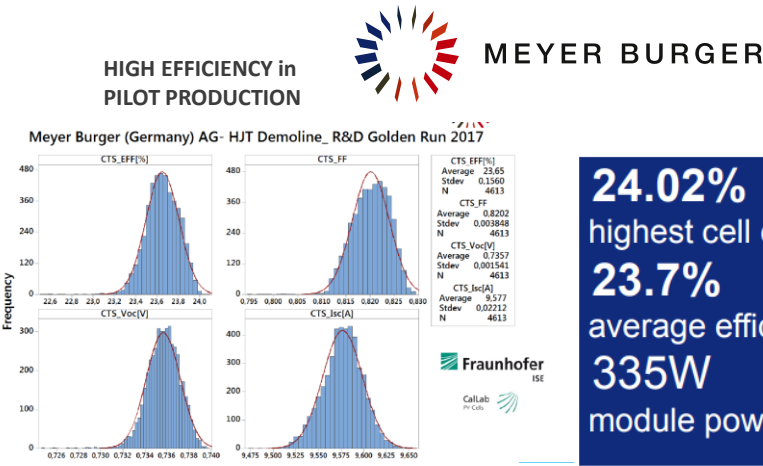
CAPEX reduction

Metallization/ Interco costs

Mass prod. demo

Upgrade roadmap



Capitalize on Tcoeff, bifacial, thin wafer



24.02%  
highest cell efficiency

23.7%  
average efficiency

335W  
module power (mono facial)



1 : PASSIVATING CONTACTS & BIFACIAL

> 24 % R&D level


CAPEX reduction

Metallization/ Interco costs

Mass prod. demo

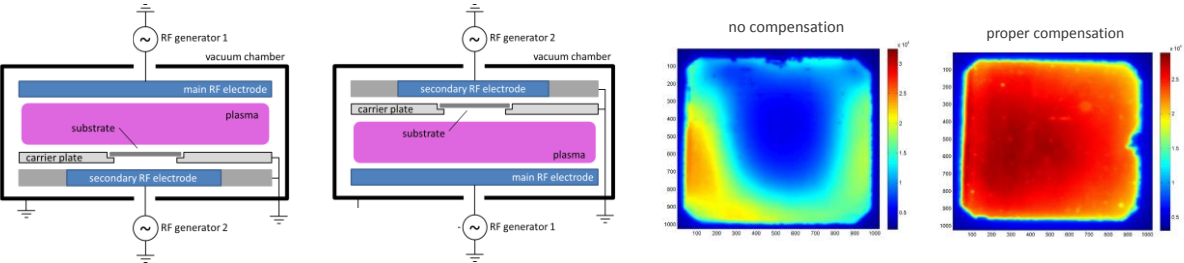
Upgrade roadmap

Capitalize on Tcoeff, bifacial, thin wafer



INDEOtec  
PLASMA PROCESS EQUIPMENT

Alternative PECVD reactor :  
MIRROR Concept: Both-sides deposition without vacuum break/no flipping of wafer  
Cross contamination management: i/n in 1 reactor, i/p in 1 reactor  
Parallelism





1 : PASSIVATING CONTACTS & BIFACIAL



SMARTWIRE TECHNOLOGY BENEFITS

- Less shading
- Less resistivity losses
- Cell paste usage reduction (up to 70%)
- Better resistance for micro cracks
- Low temperature and low thermal stress interconnection technology
- No alignment needed (≠ MBB)
- Aesthetically attractive

> 24 % R&D level

CAPEX reduction

Metallization/ Interco costs

Mass prod. demo

Upgrade roadmap

Capitalize on Tcoeff, bifacial, thin wafer

Front  
25 mg

BBless

Front  
125 mg

SBB

Ag cost = 1.3 \$cent/cell

Ag cost = 6.8 \$cent/cell

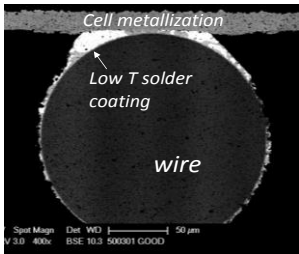


1 : PASSIVATING CONTACTS & BIFACIAL

NEW GENERATION SMARTWIRE

Cost decrease in wires : Indium-free low temperature alloy coating on wires  
Performance increase : + 2% from new design & UV-through

Demonstration of metallurgical bonding btw. HJT cell finger and a wire w. selected Indium free low T solder satisfying above criteria.



> 24 % R&D level

CAPEX reduction

Metallization/ Interco costs

Mass prod. demo

Upgrade roadmap

Capitalize on Tcoeff, bifacial, thin wafer

**Reliability (HJT):**  
PTC < 1% degradation after 3xIEC  
DH < 2% degradation after 3xIEC  
**Reliability (PERC):**  
PTC < 1% degradation after 3xIEC  
DH < 3% degradation after 2xIEC



1 : PASSIVATING CONTACTS & BIFACIAL

> 24 % R&D level

CAPEX reduction

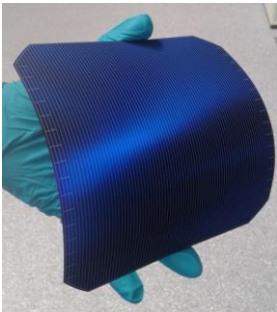
Metallization/ Interco costs

Mass prod. demo

Upgrade roadmap

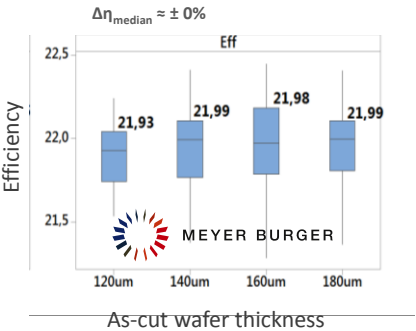
Capitalize on Tcoeff, bifacial, thin wafer

p-type wafer 180µm: ~ 62 \$cts/wafer  
n-type wafer 180µm: ~ 68 \$cts/wafer  
**Cost decrease w. thickness: 1.5 \$cts/10 µm**  
n-type wafer 120µm: ~ 59 \$cts/wafer

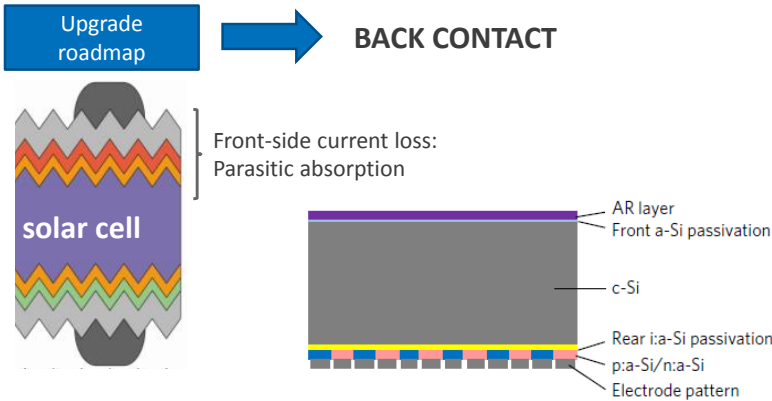


Thin wafer integration in production:  
potential for down to 120 µm as-cut  
demonstrated by Meyer Burger.

- Excellent surface passivation permits no performance loss ( $J_{sc}$  loss,  $V_{oc}$  gain).
- Bifacial structure equilibrates stress on both cell sides.

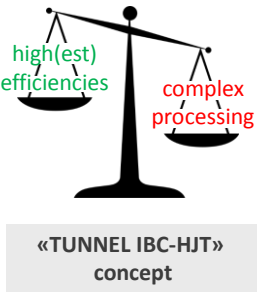


2 : BACK CONTACTS w. PASSIVATING CONTACTS



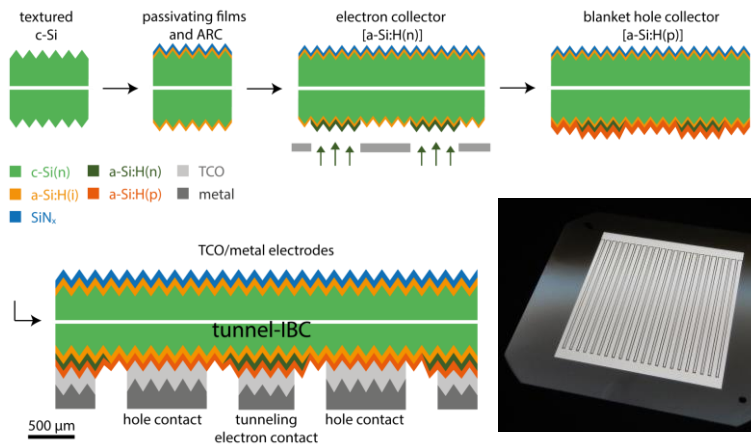
Highest efficiency potential demonstrated:  
world record – Kaneka / 26.6 %  
[K. Yoshikawa, Nature Energy 2, 17032 (2017)]

Challenge for cost-effective manufacturing keeping high efficiency.

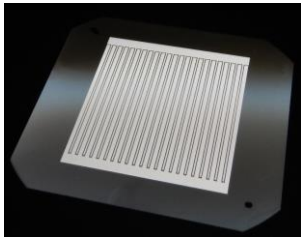




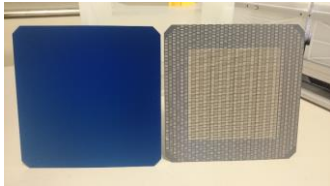
2 : BACK CONTACTS w. PASSIVATING CONTACTS



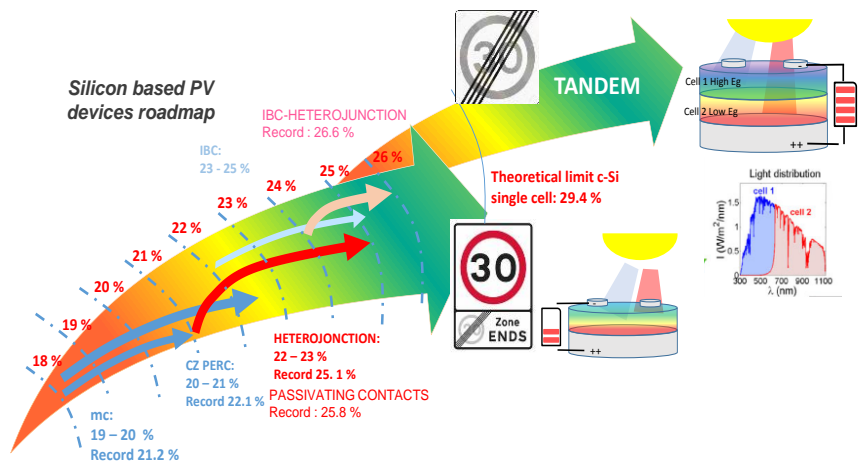
SIMPLE PROCESS FLOW  
MINIMIZATION OF MATERIALS  
**HIGH EFFICIENCY demonstrated**  
so far up to 24.1 %




**MEYER BURGER**  
Transfer to full wafer  
industrial processing.



EFFICIENCY DRIVEN TECHNOLOGY UPGRADE



3 : SILICON BASED TANDEM CELLS



**III-V/Si**

**World records:**

- 32.8 % 4-terminal tandem III-V on Silicon HJT.
- 35.9 % 4-terminal triple junction III-V on Silicon HJT

↓

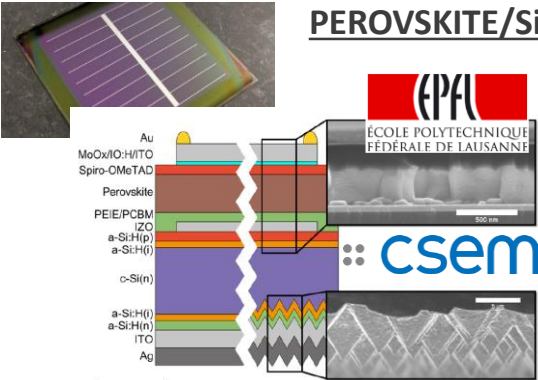
Breakthrough in III-V manufacturing with drastic costs reduction

↓

New Integration approach

↓


Alternative top cell material w. low cost potential



**PEROVSKITE/Si**

**> 25 % certified efficiency for monolithic PK/Si tandem achieved at EPFL/CSEM**

➡ See poster of Quentin Jeangros - EPFL



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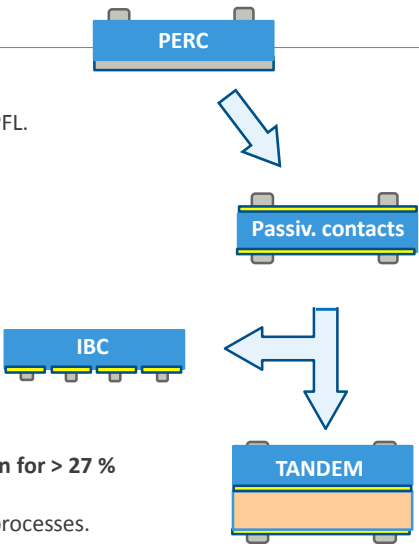
CONCLUSION

**PASSIVATING CONTACTS to extend cell efficiency > 24 %:**  
High temperature approaches w. SiOx/SiCx developed at CSEM/EPFL.  
High electrical properties. Lean process flow to demonstrate.

Silicon Heterojunction w. > 24 % at CSEM.  
Simple process flow, thin wafers, bifacial, lowest LCOE. Advanced manufacturing developed w. Swiss industry.

**BACK CONTACTS to extend cell efficiency > 25-26 %:**  
Simple process flow «TUNNEL-IBC» developed at CSEM/EPFL.  
In transfer to Swiss industry.

**Perovskite as add-on technology to Silicon for > 27 %**  
> 25 % demonstrated by EPFL/CSEM.  
Work on higher eff., reliability, industrial processes.



Thank you to all colleagues & partners





Schweizerische Eidgenossenschaft  
Confédération suisse  
Confederazione Svizzera  
Confederaziun svizra

**Bundesamt für Energie BFE**  
**Office fédéral de l'énergie OFEN**



Schweizerische Eidgenossenschaft  
Confédération suisse  
Confederazione Svizzera  
Confederaziun svizra

Swiss Confederation

**Innosuisse – Swiss Innovation Agency**



Schweizerische Eidgenossenschaft  
Confédération suisse  
Confederazione Svizzera  
Confederaziun svizra

Département fédéral de l'économie,  
de la formation et de la recherche DEFR  
**Secrétariat d'Etat à la formation,  
à la recherche et à l'innovation SEFRI**

Thank you for  
your attention

CSEM PV Facade HJT cells  
«Solar Visualised in Europe Award»



SmartWire  
Heterojunction  
PV facade  
CSEM